1/20/2015

RELIABILITY MONITOR REPORT
FOR

MFN 1.2µm Silicon Gate (S12)

MAXIM INTEGRATED

160 RIO ROBLES
SAN JOSE, CA 95134

This Report was prepared by
MAXIM INTEGRATED Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX1932ETC+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 8720 QUANTITY: 45 FAILS: 0 FITS: 13.1

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 1/1/2014 and 12/31/2014.

Process Information:

Process Description: MFN 1.2µm Silicon Gate (S12)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1427	MAX1932ETC+	135°C	1000 HRS	45	0	NJ60AA135D
				Total:		**0**	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1427	MAX1932ETC+	-65C TO +150C (Condition C)	500 CYS	80	0	NJ60AA135D
				Total:		**0**	

FAILURE RATE: MTTF (YRS): 8720 QUANTITY: 45 FAILS: 0 FITS: 13.1